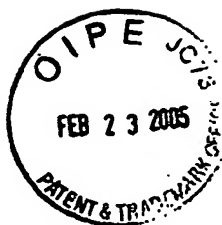


2/05



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent Appl. Publication No.</u>	<u>Inventor/ Applicant</u>
245545US2*	10/803,256	03/19/04	2004/0185358 A1	KAMI
263007US0	11/007,784	12/9/04		KONDO, et al.
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*Present Application; listed for information
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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 245545US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hidetoshi KAMI			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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	AB	6,030,733	02/29/00	Hidetoshi KAMI, et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AG	11-133825	05/21/99	Japan (with English Abstract)			X
	AH	2002-123067	04/26/02	Japan (with English Abstract)			X
	AI	10-177261	06/30/98	Japan (with English Abstract)			X
	AJ	10-115946	05/06/98	Japan (with English Abstract)			X
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	AY	10-69104	03/10/98	Japan (with English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AZ				<input type="checkbox"/> Additional References sheet(s) attached		
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 245545US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hidetoshi KAMI			
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FOREIGN PATENT DOCUMENTS							
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					YES	NO	
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	AAT	2001-117244	04/27/01	Japan (with English Abstract)		X	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AAV						
	AAW						
	AAX						
	AAZ						
Examiner					Date Considered		
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